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FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. TI-14124D.5	SERIAL NO. div. of 10/649,274
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Lee D. Whetsel	
				FILING DATE October 20, 2003	GROUP TBB 2133
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